

MILITARY SPECIFICATION
MICROCIRCUITS, DIGITAL, TTL, EXCLUSIVE-OR
GATES MONOLITHIC SILICON

This amendment forms a part of Military Specification MIL-M-38510/7B, dated 21 June 1975, and is approved for use by all Departments and Agencies of the Department of Defense.

PAGE 1

1.2, delete (including example of part number) and substitute:

"1.2 Part number. The part number shall be in accordance with MIL-M-38510."

PAGE 5

FIGURE 3, schematic circuits: Delete and substitute new circuits as printed on pages 3 and 4 of this amendment.

* FIGURE 3, schematic circuits: Delete and substitute new circuit C as printed on page 4 of this amendment.

PAGE 8

TABLE II, MIL-STD-883 test requirement for end points, delete and substitute:

"Groups C and D end points electrical parameters (Method 5005)."

4.2, delete and substitute:

"4.2 Qualification inspection. Qualification inspection shall be in accordance with MIL-M-38510. Inspections to be performed shall be those specified herein for groups A, B, C, and D inspections (see 4.4.1, 4.4.2, and 4.4.3)."

4.3 (a) and (c): Delete.

PAGE 9

4.4.1, first sentence: Delete "consists of the test subgroups and LTPD values shown in" and substitute "be in accordance with".

4.4.2, delete and substitute:

"4.4.2 Group B inspection. Group B inspection shall be in accordance with table II of method 5005 of MIL-STD-883."

4.4.3, delete and substitute:

"4.4.3 Groups C and D inspections. Groups C and D inspections shall be in accordance with tables III and IV of method 5005 of MIL-STD-883 and as follows:

MIL-M-38510/7B
AMENDMENT 2

- (a) End point electrical parameters shall be as specified in table II.
- (b) Subgroups 3 and 4 shall be added to the group C inspection requirements for class B devices and shall consist of the tests, conditions, and limits specified for subgroups 10 and 11 of group A.
- (c) Operating life-test (method 1005 of MIL-STD-883) conditions.
 - (1) Test condition E or E, using the circuit shown on figure 4, or equivalent.
 - (2) $T_A = 125^{\circ}\text{C}$, minimum.
 - (3) Test duration: 1,000 hours except as permitted by Appendix B of MIL-M-38510."

PAGE 11

- * TABLE III, test number 54, test limits, maximum column: Delete "42" and substitute "57".
- * TABLE III, test number 55 CKT A,B,C: Delete "A,B,C" and substitute "A,B".
- * TABLE III, add the following new test 55 CKT C as printed on page 5 of this amendment.

PAGE 14

6.6, substitutability listing, delete and substitute:

<u>"Device type</u>	<u>Commercial type</u>
01	5486 (Circuit A - SN5486 and 7486)
01	5486 (Circuit B - S5486)
01	5486 (Circuit C - 5486)
01	5486 (Circuit D - MC5486)"

NOTE: The margins of this amendment are marked with asterisks to indicate where changes (additions, corrections, deletions) from the previous amendment were made. This was done as a convenience only and the Government assumes no liability whatsoever for any inaccuracies in these notations. Bidders and contractors are cautioned to evaluate the requirements of this document based on the entire content irrespective of the marginal notations and relationship to the last previous amendment.

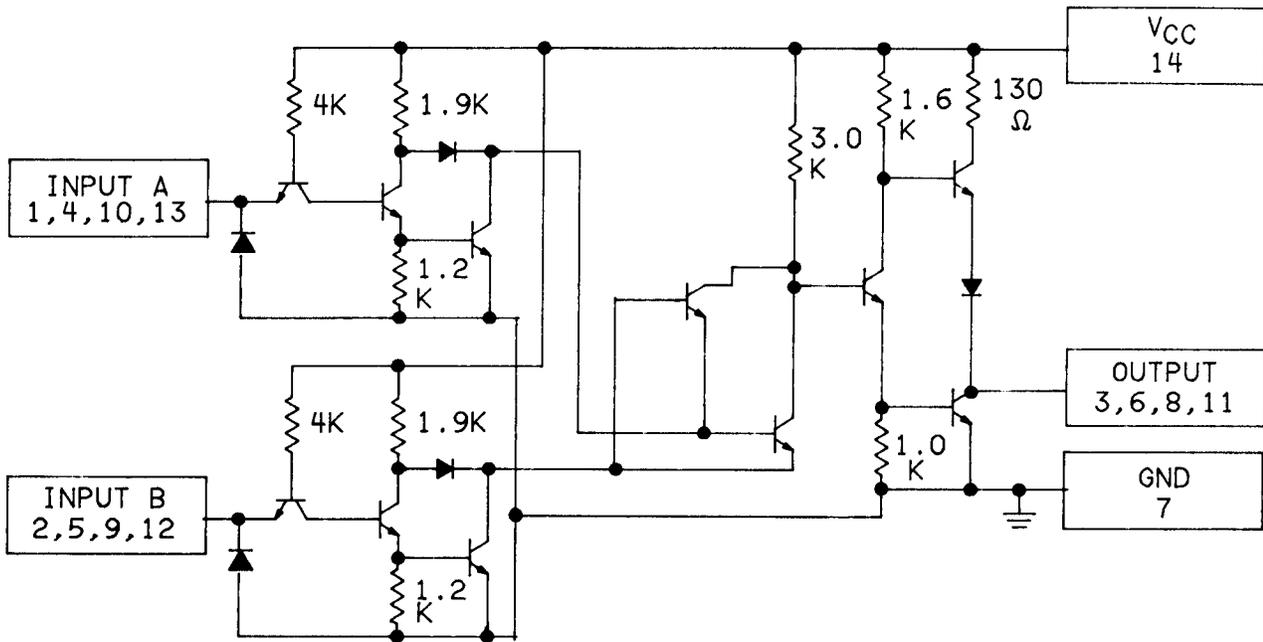
Custodians:
Army - ER
Navy - EC
Air Force - 17

Preparing activity:
Air Force - 17
(Project 5962-0461)

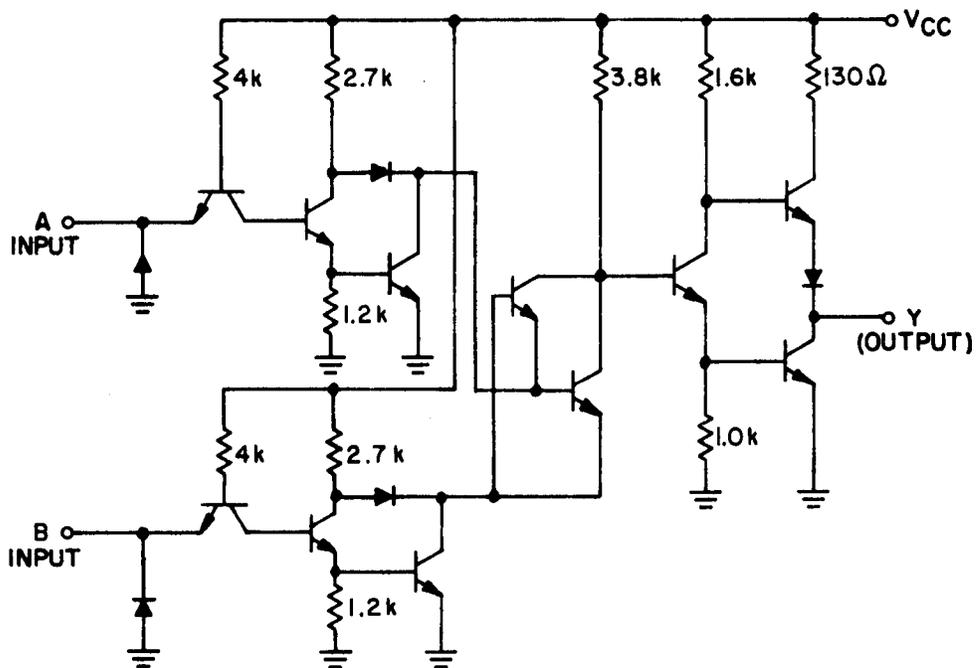
Review activities:
Army - MI, AR
Air Force - 11, 19, 85, 99
DLA - ES

User activities:
Army - SM
Navy - CG, MC, AS, OS, SH

Agent:
DLA - ES



CIRCUIT C



CIRCUIT D

NOTE:
 All resistance values shown are nominal.

FIGURE 3. Schematic circuits - Continued.

Subgroup	Symbol	MIL-STD-883 Method	Test No.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Test limits		Unit
																		Meas. Terminal	Min	
¹ T _A = 25°C	ICCL2	3005	155 CKT C	5.5 V	GND		5.5 V	V _{CC}		57	mA									